STF23N80K5



N-channel 800 V, 0.23 Ω typ., 16 A MDmesh™ K5 Power MOSFET in a TO-220FP package

Datasheet - production data

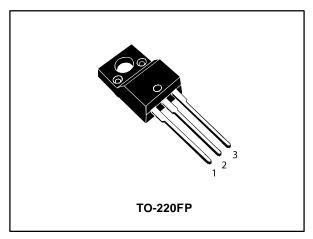
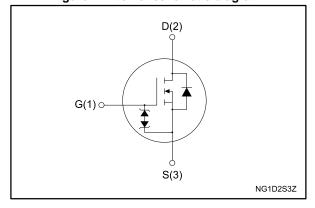


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max.	ΙD	Ртот
STF23N80K5	800 V	0.28 Ω	16 A	35 W

- Industry's lowest R_{DS(on)} x area
- Industry's best figure of merit (FoM)
- Ultra low gate charge
- 100% avalanche tested
- Zener-protected

Applications

• Switching applications

Description

This very high voltage N-channel Power MOSFET is designed using MDmesh™ K5 technology based on an innovative proprietary vertical structure. The result is a dramatic reduction in on-resistance and ultra-low gate charge for applications requiring superior power density and high efficiency.

Table 1: Device summary

Order code	Marking	Package	Packing
STF23N80K5	23N80K5	TO-220FP	Tube

Contents STF23N80K5

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STF23N80K5 Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter		Unit
V _G s	Gate-source voltage	±30	V
1-	Drain current (continuous) at T _{case} = 25 °C	16	۸
l _D	Drain current (continuous) at T _{case} = 100 °C	10	А
I _{DM} ⁽¹⁾	Drain current (pulsed)	64	Α
P _{TOT}	Total dissipation at T _{case} = 25 °C	35	
dv/dt ⁽²⁾	Peak diode recovery voltage slope	4.5	\//n a
dv/dt ⁽³⁾	MOSFET dv/dt ruggedness	50	V/ns
V _{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink (t=1 s;Tc= 25 °C)	2500	V
T _{stg}	Storage temperature	mperature -55 to 150	
Tj	Operating junction temperature	-55 10 150	°C

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	3.6	°C/W
R _{thj-amb}	Thermal resistance junction-ambient	62.5	C/VV

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit	
I _{AR} ⁽¹⁾	I _{AR} ⁽¹⁾ Avalanche current, repetitive or not repetitive			
Eas ⁽²⁾	Single pulse avalanche energy	400	mJ	

Notes:

 $^{^{(1)}}$ Pulse width is limited by safe operating area.

 $^{^{(2)}}$ IsD \leq 16 A, di/dt=100 A/µs; VDs peak < V(BR)DSS, VDD = 80% V(BR)DSS.

 $^{^{(3)}}$ V_{DS} ≤ 640 V

 $^{^{(1)}}$ Pulse width limited by T_{jmax} .

 $^{^{(2)}}$ starting $T_j = 25~^{\circ}C,~I_D = I_{AR},~V_{DD} = 50~V.$

Electrical characteristics STF23N80K5

2 Electrical characteristics

(T_{case} = 25 °C unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	800			٧
	Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 800 \text{ V}$			1	
IDSS		V _{GS} = 0 V, V _{DS} = 800 V, T _{case} = 125 °C			50	μΑ
I _{GSS}	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			±10	μΑ
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 100 \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 8 A		0.23	0.28	Ω

Table 6: Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	1000	•	
Coss	Output capacitance	V _{DS} = 100 V, f = 1 MHz,	-	65	ı	pF
Crss	Reverse transfer capacitance	V _{GS} = 0 V	-	1.5	ı	ρ.
C _{O(tr)} ⁽¹⁾	Equivalent output capacitance	$V_{DS} = 0$ to 640 V, $V_{GS} = 0$ V	-	165	ı	ر 1
C _{O(er)} ⁽²⁾	Equivalent output capacitance	V _{DS} = 0 to 640 V, V _{GS} = 0 V	-	59	-	pF
R _G	Intrinsic gate resistance	$f = 1 \text{ MHz}, I_D = 0 \text{ A}$	-	4.7	ı	Ω
Q_g	Total gate charge	$V_{DD} = 640 \text{ V}, I_D = 16 \text{ A},$	-	33	•	
Qgs	Gate-source charge	V _{GS} = 10 V (see Figure 14: "Test circuit for gate charge	-	6	-	nC
Q_{gd}	Gate-drain charge	behavior")	-	25		

Notes:

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)}	Turn-on delay time	V _{DD} = 400 V, I _D = 8 A	-	14	-	
tr	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$ (see Figure 13: "Test circuit for	-	9	-	
t _{d(off)}	Turn-off delay time	resistive load switching times"	-	48	-	ns
t _f	Fall time	and Figure 18: "Switching time waveform")	1	9	1	

 $^{^{(1)}}$ Time related is defined as a constant equivalent capacitance giving the same charging time as C_{OSS} when V_{DS} increases from 0 to 80% V_{DSS} .

 $^{^{(2)}}$ Energy related is defined as a constant equivalent capacitance giving the same stored energy as Coss when VDs increases from 0 to 80% VDss

Table 8: Source-drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		16	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		-		64	Α
V _{SD} ⁽²⁾	Forward on voltage	V _{GS} = 0 V, I _{SD} = 16 A	-		1.5	V
t _{rr}	Reverse recovery time	$I_{SD} = 16 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	410		ns
Qrr	Reverse recovery charge	V _{DD} = 60 V (see Figure 15: "Test circuit for inductive load	-	7		μC
I _{RRM}	Reverse recovery current	switching and diode recovery times")	ı	34		Α
t _{rr}	Reverse recovery time	$I_{SD} = 16 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	650		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150 \text{ °C}$ (see Figure 15: "Test circuit for	-	10		μC
I _{RRM}	Reverse recovery current	inductive load switching and diode recovery times")	-	32		Α

Notes:

Table 9: Gate-source Zener diode

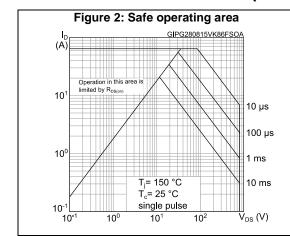
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)GSO}$	Gate-source breakdown voltage	$I_{GS} = \pm 1 \text{ mA}, I_D = 0 \text{ A}$	±30	-	-	V

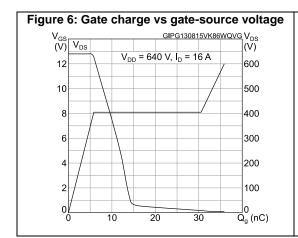
The built-in back-to-back Zener diodes are specifically designed to enhance the ESD performance of the device. The Zener voltage facilitates efficient and cost-effective device integrity protection, thus eliminating the need for additional external componentry.

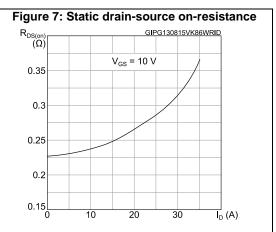
⁽¹⁾ Pulse width is limited by safe operating area.

 $^{^{(2)}}$ Pulse test: pulse duration = 300 μ s, duty cycle 1.5%.

2.1 Electrical characteristics (curves)







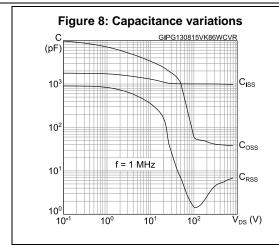


Figure 9: Normalized gate threshold voltage vs temperature

V_{GS(th)}

GIPG130815VK86WVTH

(norm.)

1.2

1.0

0.8

0.6

0.4

0.2

-50

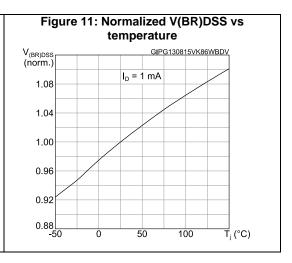
0 50

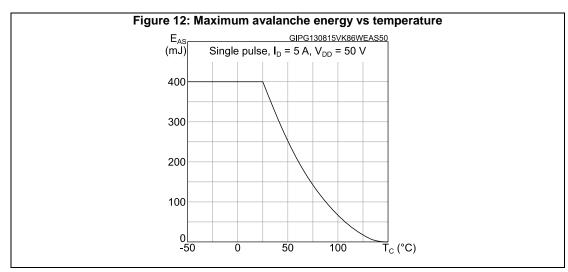
100

T_j(°C)

Figure 10: Normalized on-resistance vs temperature

R_{DS(on)} GIPG130815VK86WRON
(norm.)
2.6
2.2
1.8
1.4
1.0
0.6
0.2
-50
0
50
100
T_j (°C)





Test circuits STF23N80K5

3 Test circuits

Figure 13: Test circuit for resistive load switching times

Figure 14: Test circuit for gate charge behavior

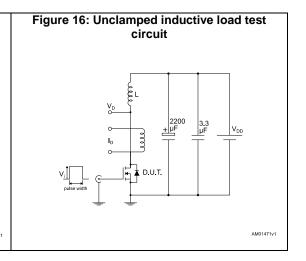
12 V 47 kΩ 100 nF 1 kΩ

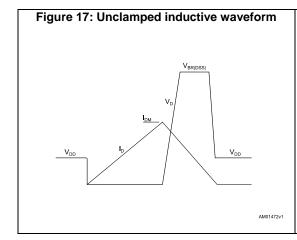
Vos 1 kΩ 1 kΩ

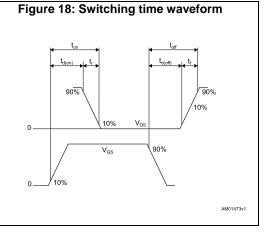
Vos 1 kΩ 1 kΩ

AM01466y1

Figure 15: Test circuit for inductive load switching and diode recovery times







STF23N80K5 Package information

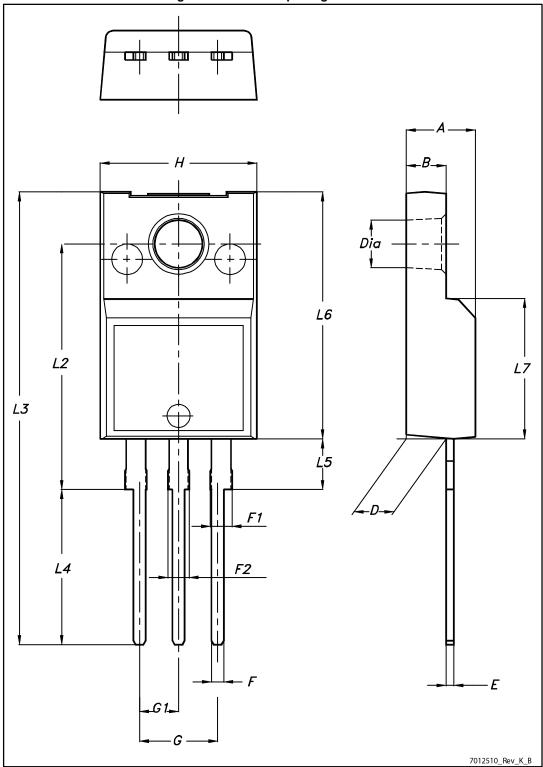
4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.



4.1 TO-220FP package information

Figure 19: TO-220FP package outline



STF23N80K5

Table 10: TO-220FP package mechanical data

Di	mm			
Dim.	Min.	Тур.	Max.	
А	4.4		4.6	
В	2.5		2.7	
D	2.5		2.75	
Е	0.45		0.7	
F	0.75		1	
F1	1.15		1.70	
F2	1.15		1.70	
G	4.95		5.2	
G1	2.4		2.7	
Н	10		10.4	
L2		16		
L3	28.6		30.6	
L4	9.8		10.6	
L5	2.9		3.6	
L6	15.9		16.4	
L7	9		9.3	
Dia	3		3.2	

Revision history STF23N80K5

5 Revision history

Table 11: Document revision history

Date	Revision	Changes
28-Aug-2015	1	First release.

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